BUK7C06-40AITE

N-channel TrenchPLUS standard level FET

Rev. 05 — 16 February 2009

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. The devices include TrenchPLUS current sensing and diodes for ElectroStatic Discharge (ESD) protection and temperature sensing. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Allows responsive temperature monitoring due to integrated temperature sensor
- Electrostatically robust due to integrated protection diodes
- Low conduction losses due to low on-state resistance
- Q101 compliant
- Reduced component count due to integrated current sensor

1.3 Applications

- Automotive and general purpose power switching
- Electrical Power Assisted Steering (EPAS)
- Fan control
- Variable valve timing for engines

1.4 Quick reference data

Table 1. Quick reference

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|------------------------------------|---|---|------|-------|-------|------|
| V_{DS} | drain-source voltage | $T_j \ge 25 \mathcal{C}; T_j \le 175 \mathcal{C}$ | - | - | 40 | V |
| I_D | drain current | $V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ C}; \text{ see } \frac{\text{Figure 2}}{\text{1}}; \text$ | - | - | 155 | Α |
| Static cha | racteristics | | | | | |
| R _{DSon} | drain-source on-state resistance | $V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 25 \text{ C}; \text{ see}$ Figure 7; see Figure 8 | - | 4.7 | 6 | mΩ |
| I _D /I _{sense} | ratio of drain current to sense current | $T_j > -55 \text{°C}; T_j < 175 \text{°C}; V_{GS} = 10 \text{V}$ | 585 | 615 | 645 | |
| S _{F(TSD)} | temperature sense diode temperature coefficient | $I_F = 250 \mu A; T_j > -55 ^{\circ}C; T_j < 175 ^{\circ}C$ | -1.4 | -1.54 | -1.68 | mV/K |
| $V_{F(TSD)}$ | temperature sense diode forward voltage | $I_F = 250 \mu A; T_j = 25 ^{\circ}C$ | 648 | 658 | 668 | mV |

[1] Current is limited by power dissipation chip rating.



2. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-----------------------------------|--------------------|--|
| 1 | G | gate | | |
| 2 | ISENSE | Current sense | mb | D A |
| 3 | Α | anode | | ,+ |
| 4 | D | drain | | G ↓ ↓ ↑ ↑ ↑ ↑ |
| 5 | K | cathode | 7002000 | 歩片 |
| 6 | KS | Kelvin source | ∐∐∐ ∐∐∐ 123 567 | |
| 7 | S | source | SOT427 | |
| mb | D | mounting base; connected to drain | (D2PAK) | l _{sense} Ś │ K Kelvin source <i>sym110</i> |

3. Ordering information

Table 3. Ordering information

| Type number | Package | 'ackage | | | | |
|----------------|---------|--|---------|--|--|--|
| | Name | Description | Version | | | |
| BUK7C06-40AITE | D2PAK | plastic single-ended surface-mounted package (D2PAK); 7 leads (one lead cropped) | SOT427 | | | |

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | | Min | Max | Unit |
|--------------------------------|--|---|-----|------|------|--------------|
| V_{DS} | drain-source voltage | $T_j \ge 25 \text{°C}; T_j \le 175 \text{°C}$ | | - | 40 | V |
| V_{DGR} | drain-gate voltage | $R_{GS} = 20 \text{ k}\Omega$ | | - | 40 | V |
| V_{GS} | gate-source voltage | | | -20 | 20 | V |
| I _D | drain current | T_{mb} = 25 °C; V _{GS} = 10 V; see <u>Figure 2</u> ; see <u>Figure 3</u> | [1] | - | 155 | Α |
| | | | [2] | - | 75 | Α |
| | | $T_{mb} = 100 \text{C}$; $V_{GS} = 10 \text{V}$; see Figure 2 | [2] | - | 75 | Α |
| I_{DM} | peak drain current | $T_{mb} = 25 C; t_p \le 10 \mu\text{s}; \text{ pulsed}; \text{ see } \underline{\text{Figure 3}}$ | | - | 620 | Α |
| P _{tot} | total power dissipation | $T_{mb} = 25 \text{°C}$; see Figure 1 | | - | 272 | W |
| I _{GS(CL)} | gate-source clamping | continuous | | - | 10 | mΑ |
| | current | pulsed; $t_p = 5$ ms; $\delta = 0.01$ | | - | 50 | mΑ |
| V _{isol(FET-TS} D) | FET to temperature sense diode isolation voltage | | | -100 | 100 | V |
| T _{stg} | storage temperature | | | -55 | 175 | $\mathcal C$ |
| Tj | junction temperature | | | -55 | 175 | $\mathcal C$ |
| Source-dra | ain diode | | | | | |
| I _S | source current | $T_{mb} = 25 $ C | [1] | - | 155 | Α |
| | | | [2] | - | 75 | Α |
| I _{SM} | peak source current | $t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}\!$ | | - | 620 | Α |
| Avalanche | ruggedness | | | | | |
| E _{DS(AL)S} | non-repetitive drain-source avalanche energy | I_D = 75 A; V_{sup} ≤ 40 V; R_{GS} = 50 Ω; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped | | - | 1.46 | J |
| Electrostat | tic discharge | | | | | |
| V _{esd} | electrostatic discharge voltage | HBM; C = 100 pF; R = 1.5 kΩ | | - | 6 | kV |

^[1] Current is limited by power dissipation chip rating.

^[2] Continuous current is limited by package.

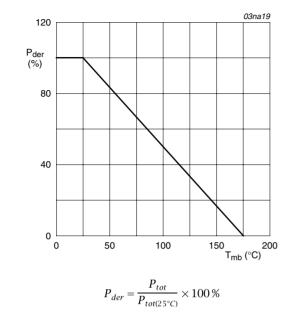
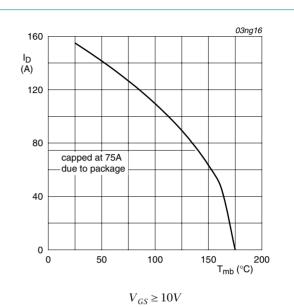


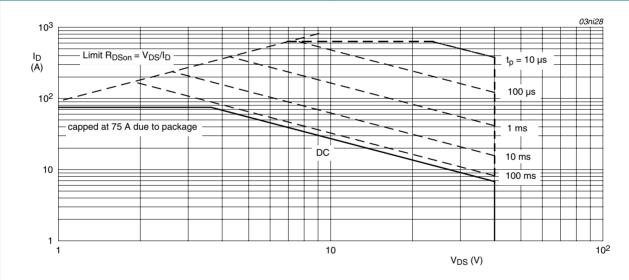
Fig 1. Normalized total power dissipation as a function of mounting base temperature

Product data sheet



Continuous drain current as a function of Fig 2. mounting base temperature

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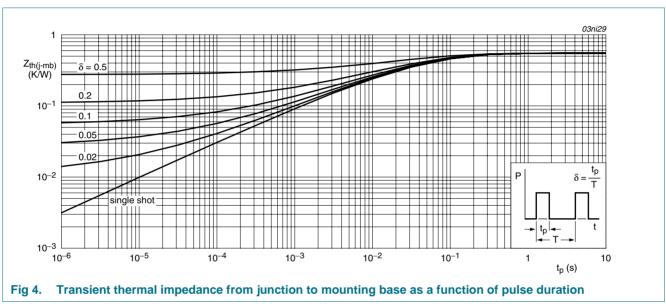
 $T_{mb} = 25$ °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

Thermal characteristics 5.

Table 5. **Thermal characteristics**

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|----------------|---|---|-----|-----|------|------|
| $R_{th(j-a)}$ | thermal resistance from junction to ambient | mounted on printed-circuit board; minimum footprint | - | - | 50 | K/W |
| $R_{th(j-mb)}$ | thermal resistance from junction to mounting base | see Figure 4 | - | - | 0.55 | K/W |



6. Characteristics

Table 6. Characteristics

| Table 6. | Characteristics | O 11/1 | | | | |
|------------------------------------|--|---|------|-------|-------|------|
| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
| | racteristics | | | | | |
| $V_{(BR)DSS}$ | drain-source | $I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$ | 40 | - | - | V |
| | breakdown voltage | $I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 ^{\circ}\text{C}$ | 36 | - | - | V |
| $V_{GS(th)}$ | gate-source threshold voltage | $I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 25 \text{ °C}$; see Figure 9 | 2 | 3 | 4 | V |
| | | $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 ^{\circ}\text{C};$ see Figure 9 | 1 | - | - | V |
| | | $I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 ^{\circ}\text{C}$; see Figure 9 | - | - | 4.4 | V |
| I _{DSS} | drain leakage current | $V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$ | - | 0.1 | 10 | μΑ |
| | | $V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 ^{\circ}\text{C}$ | - | - | 250 | μΑ |
| $V_{(BR)GSS}$ | gate-source breakdown voltage | $I_G = 1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j > -55 \text{ C};$ $T_j < 175 \text{ C}$ | 20 | 22 | - | V |
| | | $I_G = -1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j > -55 \text{ C};$ $T_j < 175 \text{ C}$ | 20 | 22 | - | V |
| I _{GSS} | gate leakage current | $V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}; T_j = 25 ^{\circ}\text{C}$ | - | 22 | 1000 | nA |
| | | $V_{DS} = 0 \text{ V}; V_{GS} = -10 \text{ V}; T_j = 25 ^{\circ}\text{C}$ | - | 22 | 1000 | nA |
| | | V _{DS} = 0 V; V _{GS} = 10 V; T _j = 175 °C | - | - | 10 | μA |
| | | V _{DS} = 0 V; V _{GS} = -10 V; T _j = 175 °C | - | - | 10 | μA |
| R _{DSon} | drain-source on-state resistance | $V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 25 \text{ C};$ see Figure 7; see Figure 8 | - | 4.7 | 6 | mΩ |
| | | $V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 175 \text{ C};$ see Figure 7; see Figure 8 | - | - | 11.4 | mΩ |
| V _{F(TSD)} | temperature sense diode forward voltage | $I_F = 250 \ \mu A; \ T_j = 25 \ ^{\circ} C$ | 648 | 658 | 668 | mV |
| S _{F(TSD)} | temperature sense diode temperature coefficient | $I_F = 250 \mu A; T_j > -55 \text{ C}; T_j < 175 \text{ C}$ | -1.4 | -1.54 | -1.68 | mV/K |
| V _{F(TSD)hys} | temperature sense diode forward voltage hysteresis | $I_F > 125 \mu A$; $I_F < 250 \mu A$; $T_j = 25 °C$ | 25 | 32 | 50 | mV |
| I _D /I _{sense} | ratio of drain current to sense current | $V_{GS} = 10 \text{ V}; T_j > -55 \text{ C}; T_j < 175 \text{ C}$ | 585 | 615 | 645 | |
| Dynamic o | haracteristics | | | | | |
| Q _{G(tot)} | total gate charge | I _D = 25 A; V _{DS} = 32 V; V _{GS} = 10 V; | - | 120 | - | nC |
| Q _{GS} | gate-source charge | $T_j = 25 \text{°C}$; see Figure 14 | - | 19 | - | nC |
| Q_{GD} | gate-drain charge | | - | 50 | - | nC |
| C _{iss} | input capacitance | V _{GS} = 0 V; V _{DS} = 25 V; f = 1 MHz; | - | 4300 | - | pF |
| C _{oss} | output capacitance | $T_j = 25 \text{C}$; see Figure 12 | - | 1400 | - | pF |
| C _{rss} | reverse transfer capacitance | | - | 820 | - | pF |

Table 6. Characteristics ... continued

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|---------------------|----------------------------|---|-----|------|-----|------|
| t _{d(on)} | turn-on delay time | $V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$ | - | 35 | - | ns |
| t _r | rise time | $R_{G(ext)} = 10 \Omega; T_j = 25 ^{\circ}C$ | - | 115 | - | ns |
| t _{d(off)} | turn-off delay time | | - | 155 | - | ns |
| t _f | fall time | | - | 110 | - | ns |
| L_D | internal drain inductance | measured from upper edge of drain mounting base to centre of die; $T_j = 25 ^{\circ}\text{C}$ | - | 2.5 | - | nΗ |
| L _S | internal source inductance | measured from source lead to source bond pad; $T_j = 25 ^{\circ}\text{C}$ | - | 7.5 | - | nΗ |
| Source-dr | ain diode | | | | | |
| V_{SD} | source-drain voltage | $I_S = 40 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ C}$; see Figure 18 | - | 0.85 | 1.2 | V |
| t _{rr} | reverse recovery time | $I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = -10 \text{ V}$; | - | 96 | - | ns |
| Q_r | recovered charge | $V_{DS} = 30 \text{ V}; T_j = 25 ^{\circ}\text{C}$ | - | 224 | - | nC |

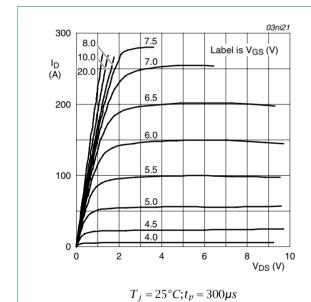


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

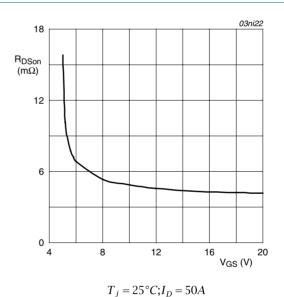


Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values

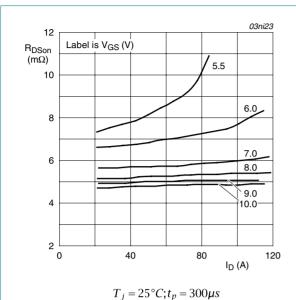


Fig 7. Drain-source on-state resistance as a function of drain current; typical values

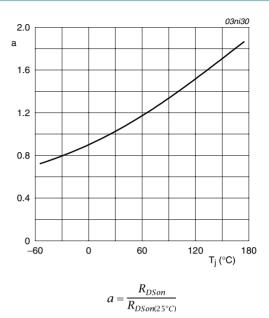


Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature

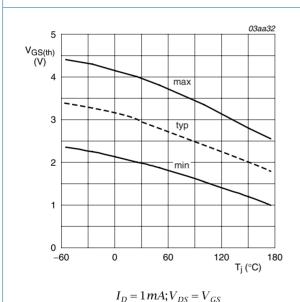
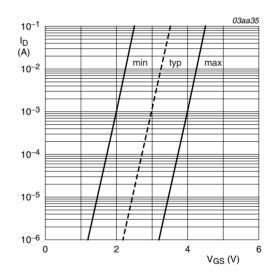


Fig 9. Gate-source threshold voltage as a function of junction temperature



 $T_j = 25 \,^{\circ}C; V_{DS} = 5V$

Fig 10. Sub-threshold drain current as a function of gate-source voltage

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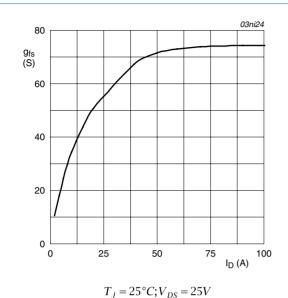
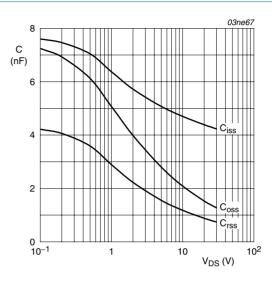


Fig 11. Forward transconductance as a function of drain current; typical values



$$V_{GS} = 0V; f = 1MHz$$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

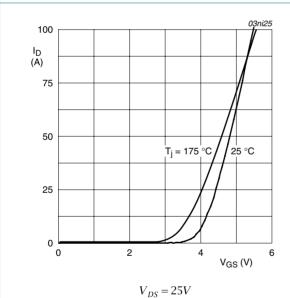
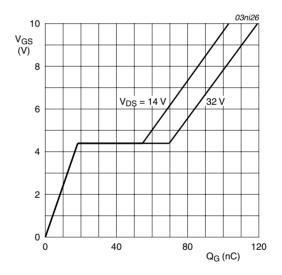


Fig 13. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $T_j = 25^{\circ}C; I_D = 25A$

Fig 14. Gate-source voltage as a function of turn-on gate charge; typical values

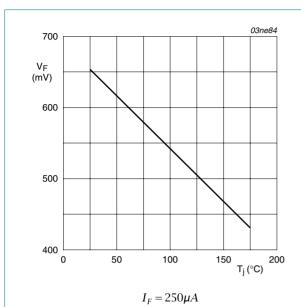
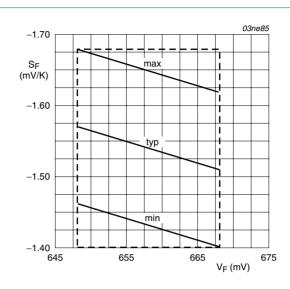


Fig 15. Forward voltage of temperature sense diode as a function of junction temperature; typical values



$$V_F$$
 at $T_j = 25$ ° C ; $I_F = 250 \mu A$

Fig 16. Temperature coefficient of temperature sense diode as a function of forward voltage; typical values

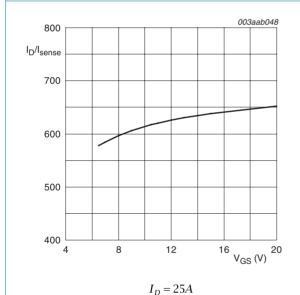


Fig 17. Drain-sense current ratio as a function of gate voltage; typical values

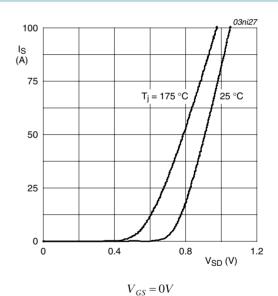
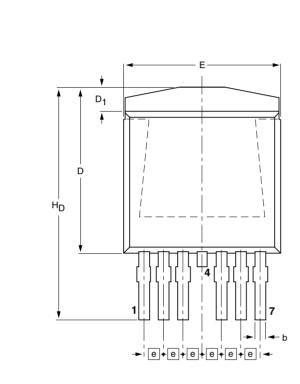


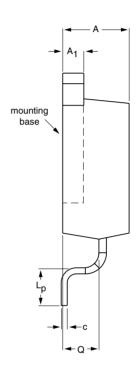
Fig 18. Source current as a function of source-drain voltage; typical values

7. Package outline

Plastic single-ended surface-mounted package (D2PAK); 7 leads (one lead cropped)

SOT427





0 2.5 5 mm scale

DIMENSIONS (mm are the original dimensions)

| UNIT | A | A ₁ | b | С | D max. | D ₁ | E | е | Lp | H _D | Q |
|------|--------------|----------------|--------------|--------------|-----------|----------------|---------------|------|--------------|----------------|--------------|
| mm | 4.50 4.10 | 1.40 1.27 | 0.85 0.60 | 0.64 0.46 | 11 | 1.60 1.20 | 10.30 9.70 | 1.27 | 2.90 2.10 | 15.80 14.80 | 2.60 2.20 |

| OUTLINE | | REFER | EUROPEAN | ISSUE DATE | | |
|---------|-----|-------|----------|------------|------------|-----------------------------------|
| VERSION | IEC | JEDEC | JEITA | | PROJECTION | ISSUE DATE |
| SOT427 | | | | | | -05-03-09 -06-03-16 |

Fig 19. Package outline SOT427 (D2PAK)

8. Revision history

Table 7. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|---------------------------------------|---------------------------------|---|------------------------|-----------------------|
| BUK7C06-40AITE_5 | 20090216 | Product data sheet | - | BUK7C06-40AITE_4 |
| Modifications: | | of this data sheet has bee of NXP Semiconductors. | n redesigned to comply | with the new identity |
| | Legal texts | have been adapted to the | new company name wh | ere appropriate. |
| BUK7C06-40AITE_4 | 20050623 | Product data sheet | - | BUK7C06-40AITE_3 |
| BUK7C06-40AITE_3 (9397 750 15176) | 20050616 | Product data sheet | - | BUK7C06_40AITE-02 |
| BUK7C06_40AITE-02 (9397 750 12487) | 20040129 | Product data sheet | - | BUK7C06_40AITE-01 |
| BUK7C06_40AITE-01 (9397 750 09873) | 20020717 | Product data sheet | - | - |

9. Legal information

9.1 Data sheet status

| Document status [1][2] | Product status[3] | Definition |
|--------------------------------|-------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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BUK7C06-40AITE

N-channel TrenchPLUS standard level FET

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